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Report No.: SZEM160900807903

Page: 1 of 6

SAR Evaluation Report

Application No.: SZEM1609008079CR
Applicant: Spigen Korea Co.,Ltd
Manufacturer/Factory: Winners'Sun Plastic & Electronic (ShenZhen) Co.,Ltd
Product Name: Selfie Stick
Model No.(EUT): S520
FCC ID: 2AFKNS520
Standards: 47 CFR Part 1.1307 (2015)
47 CFR Part 2.1093 (2015)
KDB447498D01 General RF Exposure Guidance v06
Date of Receipt: 2016-09-23
Date of Test: 2016-09-26 to 2016-09-28
Date of Issue: 2016-09-28

Test Result :	PASS*
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* In the configuration tested, the EUT complied with the standards specified above.

Authorized Signature:



Jack Zhang
EMC Laboratory Manager

The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report. If the product in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards. Any mention of SGS International Electrical Approvals or testing done by SGS International Electrical Approvals in connection with, distribution or use of the product described in this report must be approved by SGS International Electrical Approvals in writing.

The report must not be used by the client to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the federal government. All test results in this report can be traceable to National or International Standards.



2 Version

Revision Record				
Version	Chapter	Date	Modifier	Remark
00		2016-09-28		Original

Authorized for issue by:				
Tested By				2016-09-28
		<hr/>		<hr/>
		(Bill Chen) /Project Engineer		Date
Checked By				2016-09-28
		<hr/>		<hr/>
		(Eric Fu) /Reviewer		Date



3 Contents

	Page
1 COVER PAGE	1
2 VERSION	2
3 CONTENTS	3
4 GENERAL INFORMATION	4
4.1 CLIENT INFORMATION	4
4.2 GENERAL DESCRIPTION OF EUT	4
4.3 TEST LOCATION	5
4.4 TEST FACILITY	5
4.5 DEVIATION FROM STANDARDS	5
4.6 ABNORMALITIES FROM STANDARD CONDITIONS	5
4.7 OTHER INFORMATION REQUESTED BY THE CUSTOMER	5
5 SAR EVALUATION.....	6
5.1 RF EXPOSURE COMPLIANCE REQUIREMENT.....	6
5.1.1 <i>Standard Requirement</i>	6
5.1.2 <i>Limits</i>	6
5.1.3 <i>EUT RF Exposure</i>	6



4 General Information

4.1 Client Information

Applicant:	Spigen Korea Co.,Ltd
Address of Applicant:	1709 STX-V Tower, 371-37, Gasan-Dong, Geumcheon-Gu, Seoul, 153803, Korea
Manufacturer:	Winners'Sun Plastic & Electronic (ShenZhen) Co.,Ltd
Address of Manufacturer:	Zone E, Yingtai Industrial Park, Dalang South Road, Dalang Street, Baoan District, Shenzhen, China
Factory:	Winners'Sun Plastic & Electronic (ShenZhen) Co.,Ltd
Address of Factory:	Zone E, Yingtai Industrial Park, Dalang South Road, Dalang Street, Baoan District, Shenzhen, China

4.2 General Description of EUT

Product Name:	Selfie Stick
Model No.:	S520
Operation Frequency:	2402MHz~2480MHz
Bluetooth Version:	V3.0
Modulation Technique:	Frequency Hopping Spread Spectrum(FHSS)
Modulation Type:	GFSK
Number of Channel:	79
Hopping Channel Type:	Adaptive Frequency Hopping systems
Test Power Grade:	0 (manufacturer declare)
Test Software of EUT:	Blue Tool (manufacturer declare)
Sample Type:	Portable production
Antenna Type:	Integral
Antenna Gain:	-14.94dBi
Power Supply:	Model: 401120 Li - ion Polymer(charge by USB) 3.7V 60mAh
USB Cable:	Unshielded 30cm



4.3 Test Location

All tests were performed at:

SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch

No. 1 Workshop, M-10, Middle section, Science & Technology Park, Shenzhen, Guangdong, China
518057

Telephone: +86 (0) 755 2601 2053 Fax: +86 (0) 755 2671 0594

No tests were sub-contracted.

4.4 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

- **CNAS (No. CNAS L2929)**

CNAS has accredited SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch EMC Lab to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration Laboratories (CNAS-CL01 Accreditation Criteria for the Competence of Testing and Calibration Laboratories) for the competence in the field of testing.

- **A2LA (Certificate No. 3816.01)**

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory is accredited by the American Association for Laboratory Accreditation(A2LA). Certificate No. 3816.01.

- **VCCI**

The 10m Semi-anechoic chamber and Shielded Room of SGS-CSTC Standards Technical Services Co., Ltd. have been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: G-823, R-4188, T-1153 and C-2383 respectively.

- **FCC – Registration No.: 556682**

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration No.: 556682.

- **Industry Canada (IC)**

Two 3m Semi-anechoic chambers and the 10m Semi-anechoic chamber of SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch EMC Lab have been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 4620C-1, 4620C-2, 4620C-3.

4.5 Deviation from Standards

None.

4.6 Abnormalities from Standard Conditions

None.

4.7 Other Information Requested by the Customer

None.



5 SAR Evaluation

5.1 RF Exposure Compliance Requirement

5.1.1 Standard Requirement

According to KDB447498D01 General RF Exposure Guidance v06

4.3.1. Standalone SAR test exclusion considerations

Unless specifically required by the published RF exposure KDB procedures, standalone 1-g head or body and 10-g extremity SAR evaluation for general population exposure conditions, by measurement or numerical simulation, is not required when the corresponding SAR Exclusion Threshold condition, listed below, is satisfied.

5.1.2 Limits

The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$$\left[\frac{\text{(max. power of channel, including tune-up tolerance, mW)}}{\text{(min. test separation distance, mm)}} \right] \cdot \sqrt{f(\text{GHz})} \leq 3.0$$
 for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where

$f(\text{GHz})$ is the RF channel transmit frequency in GHz

Power and distance are rounded to the nearest mW and mm before calculation¹⁷

The result is rounded to one decimal place for comparison

The test exclusions are applicable only when the minimum test separation distance is ≤ 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion

5.1.3 EUT RF Exposure

The Max Conducted Peak Output Power is -3.26dBm in lowest channel(2.402GHz);

The best case gain of the antenna is -14.94dBi.

EIRP= -3.26dBm + (-14.94)dBi = -18.20dBm

-18.20dBm logarithmic terms convert to numeric result is nearly 0.0151mW

According to the formula. calculate the EIRP test result:

$$\left[\frac{\text{(max. power of channel, including tune-up tolerance, mW)}}{\text{(min. test separation distance, mm)}} \right] \cdot \sqrt{f(\text{GHz})}$$

General RF Exposure = $(0.0151\text{mW} / 5 \text{ mm}) \times \sqrt{2.402\text{GHz}} = 0.0073$ ①

SAR requirement:

S= 3.0

② ;

① < ②.

So the SAR report is not required.